

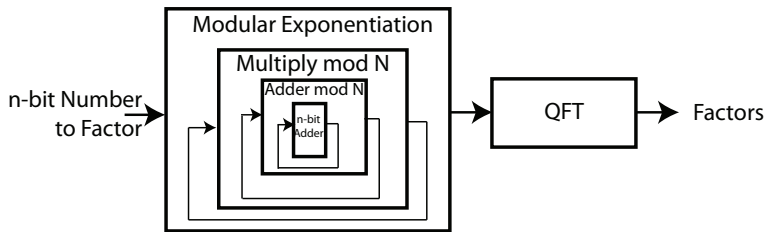
A Fault Tolerant, Area-Efficient Architecture for Shor's Factoring Algorithm

Mark Whitney, Nemanja Isailovic, Yatish Patel,
John Kubiawicz

Univ. of California, Berkeley

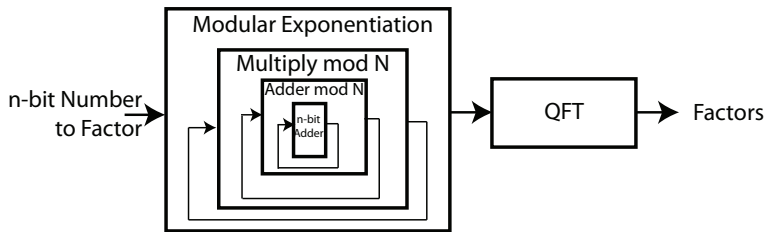
June 23, 2009

Shor's Factoring Algorithm



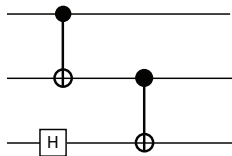
- ▶ Killer app for quantum computing
 - ▶ Runtime polynomial in number of bits
- ▶ Key component to exponentiation: quantum adder
 - ▶ 1024-bit number: billions of operations, 100,000s of qubits
- ▶ High failure rates require strong fault tolerance

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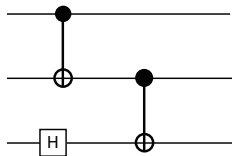


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 - ▶ 1024-bit number: billions of operations, 100,000s of qubits
- ▶ High failure rates require strong fault tolerance
 - ▶ Previous area estimates for design were $0.9m^2$
 - ▶ 95% of operations are for fault tolerance

Quantum Fault Tolerance

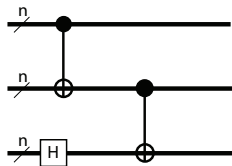


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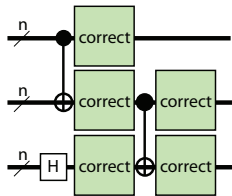
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Quantum Fault Tolerance



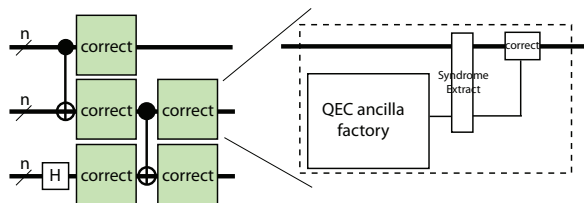
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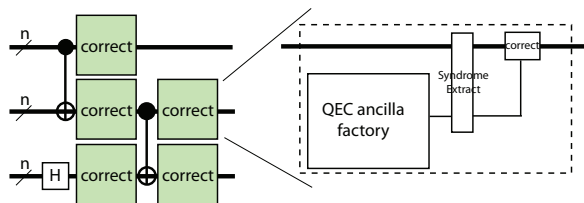
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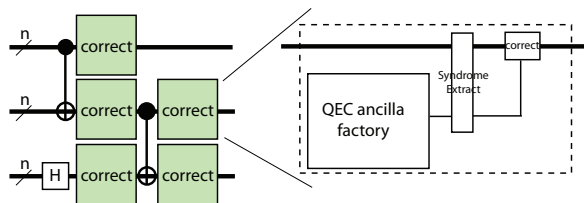
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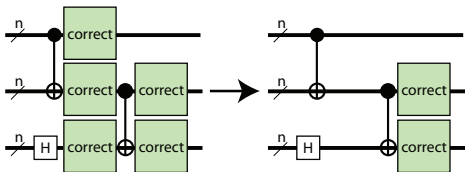
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- ▶ **Efficient design requires managing ancilla production**

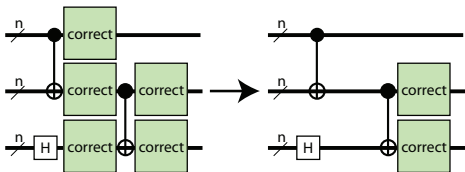
Reducing FT Overhead

- ▶ 2 choices for reducing overhead:
 - ▶ Improve ancilla supply/make more efficient
 - ▶ Decrease demand for ancilla
- ▶ Our contributions:
 - ▶ Qalypso: flexible, efficient ancilla production
 - ▶ Error correction optimization to reduce correct steps



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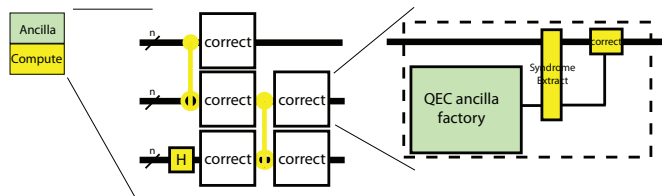


Tiled Quantum Architectures



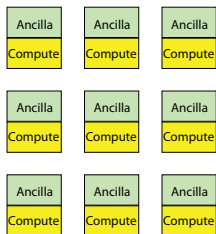
- ▶ Compute and QEC ancilla regions in a single tile

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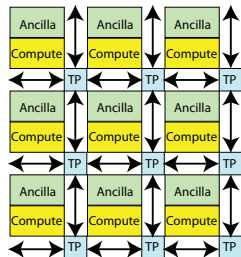
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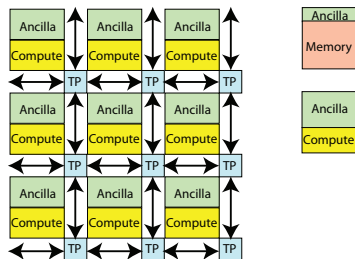
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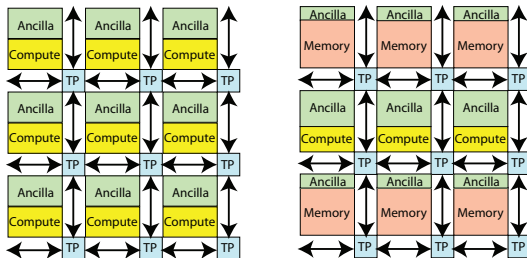
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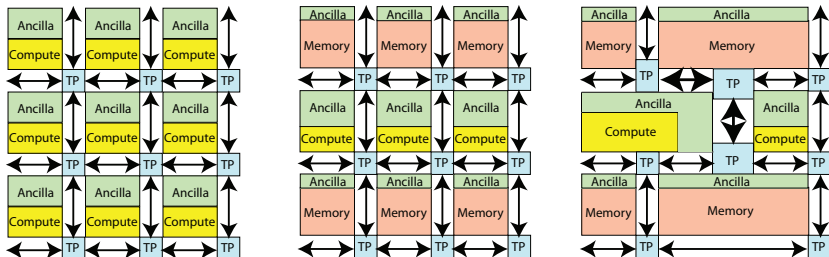
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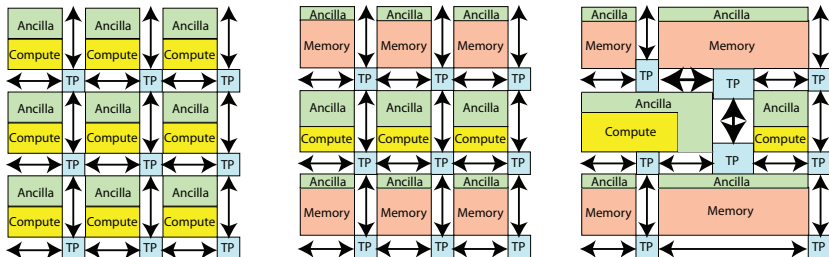
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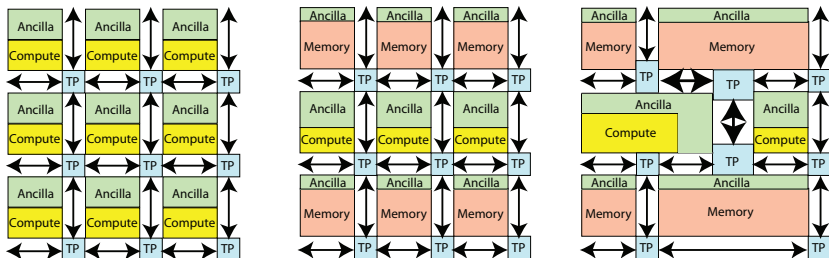
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- ▶ Our contribution: Qalypso: flexible memory, compute, QEC

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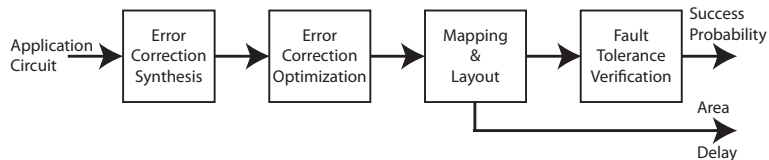
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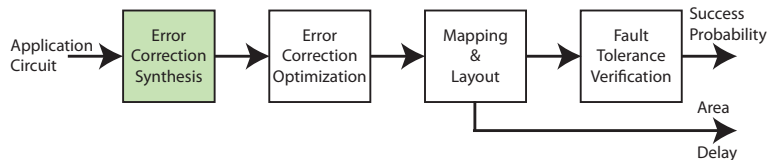
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- ▶ Parameters: number of tiles, compute/memory distribution

Computer Aided Design Flow



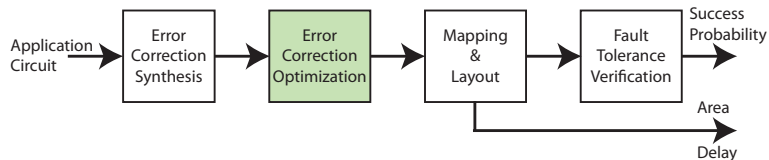
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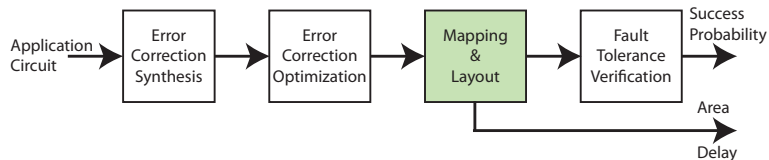
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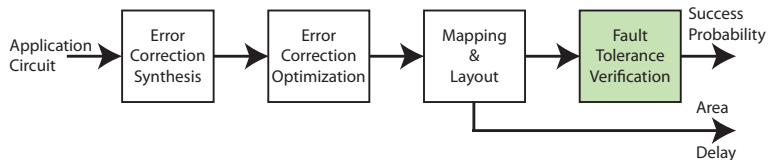
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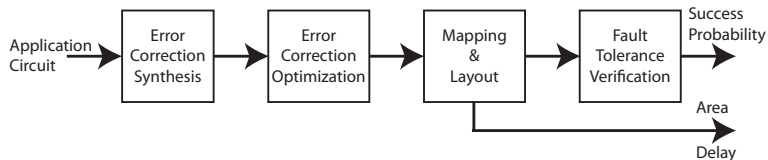
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Computer Aided Design Flow



- ▶ Input: Application circuit (Shor's, etc.)
- ▶ Output: Fault tolerant, spatial layout of circuit
- ▶ Advantages:
 - ▶ Detailed layout allows accurate comparison of designs
 - ▶ Can search large space of configurations

Metrics

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 - ▶ Area
 - ▶ Delay of single run of circuit: D_{single}

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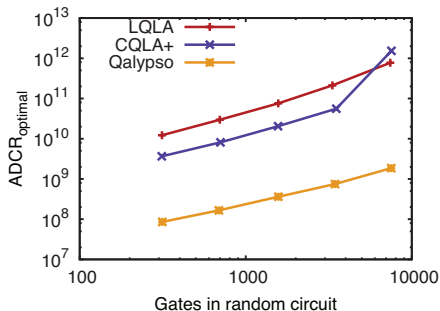
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 - ▶ Area efficiency of probabilistic circuits
- ▶ $ADCR_{optimal}$: best ADCR for over all possible configurations

Architectural Evaluation on Random Circuits

- ▶ $ADCR_{optimal}$ comparison on random circuits
- ▶ Compare best performing archs: Qalypso, LQLA, and CQLA+

Architectural Evaluation on Random Circuits

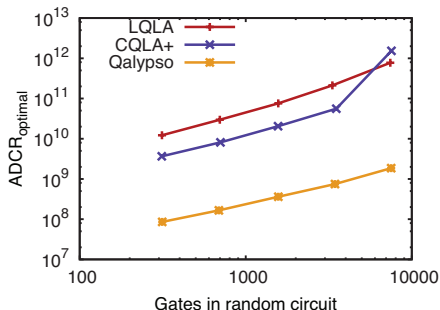
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Architectural Evaluation on Random Circuits

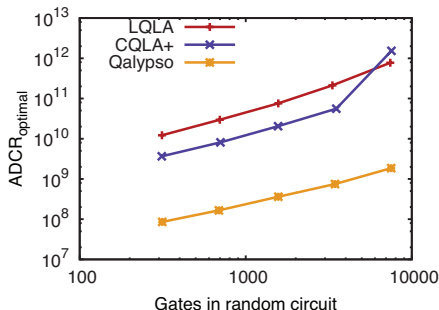
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 - ▶ 4x lower latency than LQLA
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Architectural Evaluation on Random Circuits

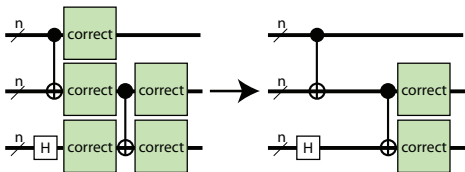
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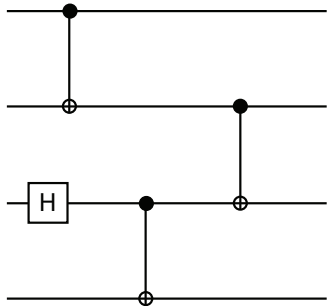
- ▶ Qalypso has significantly lower ADCR than previous work
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- ▶ Qalypso targets ancilla production to performance critical tiles

Reducing FT Overhead

- ▶ 2 choices for reducing overhead:
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 - ▶ **Decrease demand for ancilla**
- ▶ Our contributions:
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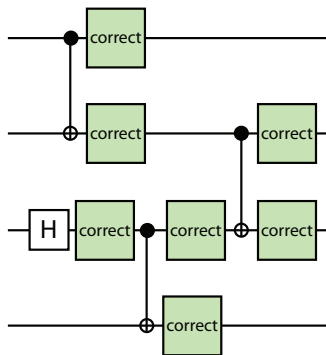


Reducing QEC Overhead



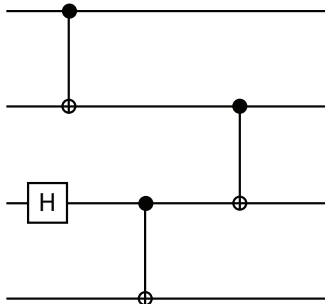
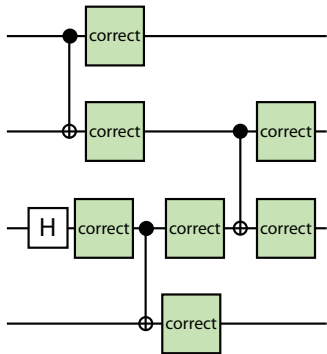
Reducing QEC Overhead

- ▶ Standard approach: insert error correction steps everywhere



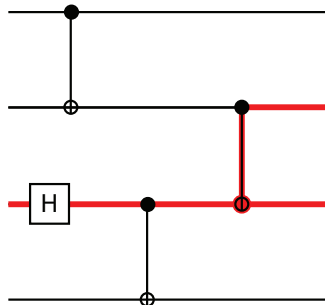
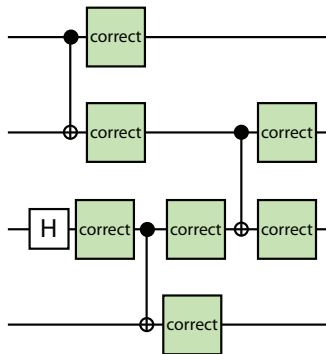
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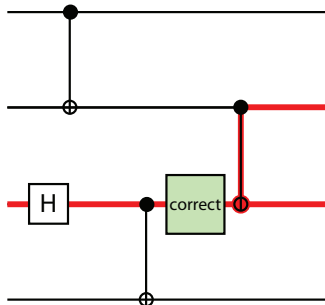
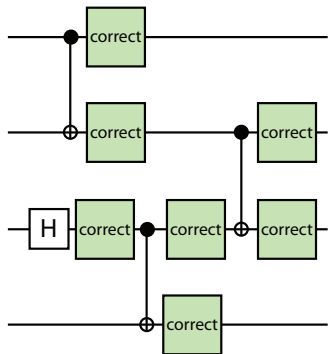
Reducing QEC Overhead

- ▶ Standard approach: insert error correction steps everywhere
- ▶ Our approach:
 - ▶ Identify critical error paths



Reducing QEC Overhead

- ▶ Standard approach: insert error correction steps everywhere
- ▶ Our approach:
 - ▶ Identify critical error paths
 - ▶ Add correction steps where “most important”

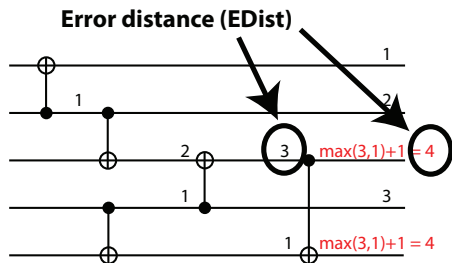


Simple Error Model for FT Circuits

- ▶ Identifying critical error paths

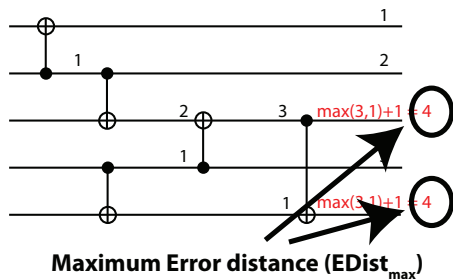
Simple Error Model for FT Circuits

- ▶ Identifying critical error paths
 - ▶ Gates propagate max input error distance to all outputs
 - ▶ Gates add 1 to error distance



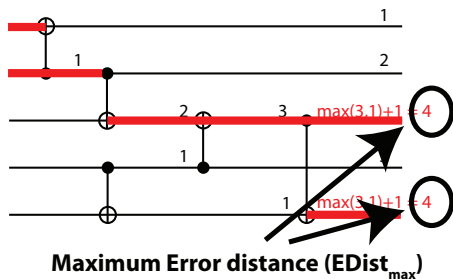
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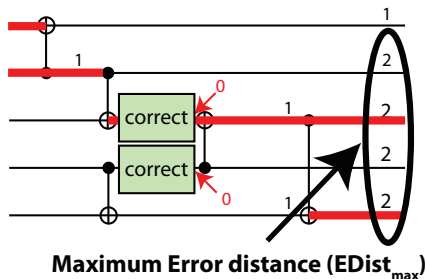
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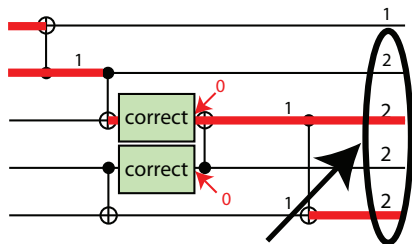
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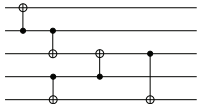
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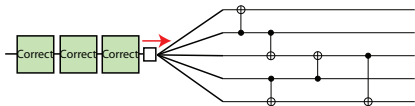
Maximum Error distance ($EDist_{max}$)

- ▶ Similar to delay in synchronous circuits
- ▶ Apply classical retiming approach: recorection
 - ▶ Corrections balance $EDist$ → Synch registers balance delay

QEC Optimization Through Circuit Recorrection

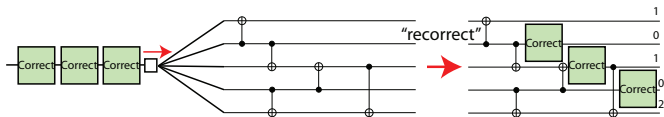


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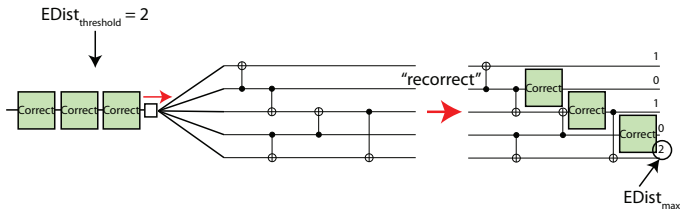
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QEC Optimization Through Circuit Recorrection



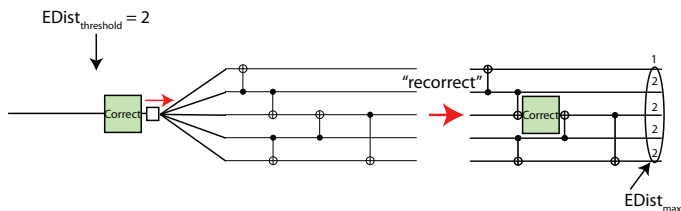
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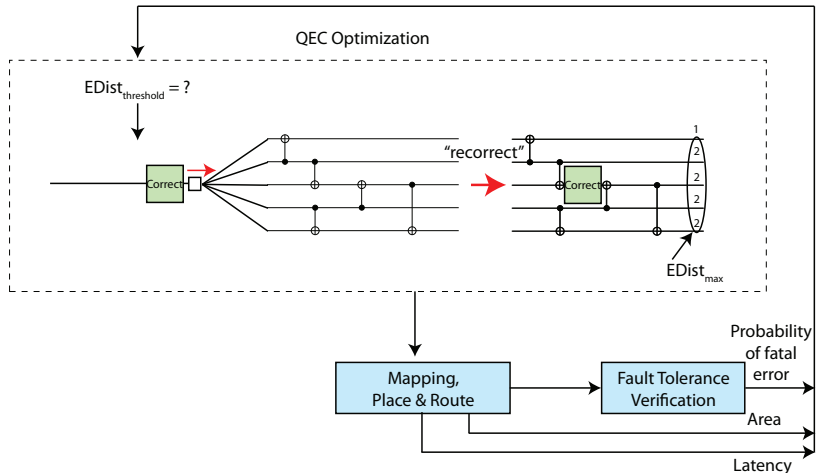
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 - ▶ Add enough corrects to reach a target $EDist_{\text{threshold}}$

QEC Optimization Through Circuit Recorrection



- ▶ Add correct ops at front of circuit
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- ▶ Find minimal number of corrects so $EDist_{max} \leq EDist_{threshold}$

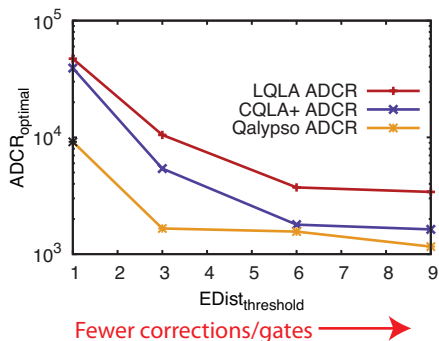
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- ▶ Add correct ops at front of circuit
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- ▶ Find $EDist_{threshold}$ for desired $p_{success}/area/D_{single}/ADCR$

Optimization and Adder Performance

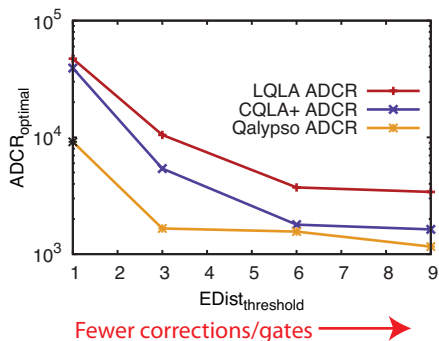
► 1024-bit Quantum Carry Lookahead Adder



► Higher $EDist_{threshold}$ = fewer corrections, more optimization

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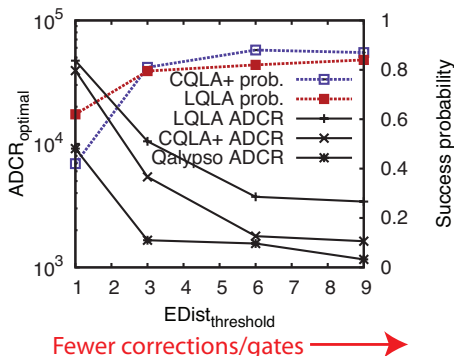
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- $6x$ improvement for Qalypso

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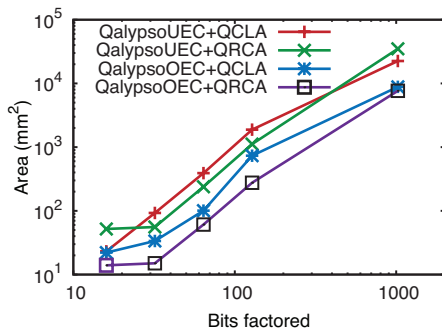
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- ▶ $6\times$ improvement for Qalypto

Shor's Performance

- ▶ Full Shor's factorization - billions of ops for 1024
- ▶ Include ripple carry adder design
- ▶ 2x reduction in latency for optimization (QCLA opt best)

Shor's Performance

- ▶ Full Shor's factorization - billions of ops for 1024
- ▶ Include ripple carry adder design
- ▶ 2x reduction in latency for optimization (QCLA opt best)



- ▶ 5x reduction in area for optimization (QRCA opt best)
- ▶ Best optimized Qalypso 1024-bit design is approx 0.01m^2

Conclusion

- ▶ ADCR: New metric for evaluating FT quantum circuits
 - ▶ Area efficiency metric including reliability, area, delay
- ▶ Qalypso outperforms other QC architectures
 - ▶ Detailed layout and simulation allows accurate comparison
 - ▶ CAD flow enables automated search of configuration space
- ▶ Error correction optimization reduces area and latency
 - ▶ Minimal impact to reliability
- ▶ Together orders of magnitude area improvement for Shor's factoring